L Number	Hits	Search Text	DB	Time stamp
1	4957	"5" and (((relay relays relayed relaying switch switching switched	USPAT;	2003/06/10 14:45
	,,,,,	switches) with circuit) and ((fanout "fan out" serial-to-parallel	US-PGPUB;	
		multiplex\$3) near (relay relays relayed relaying switch switching	EPO; JPO;	
		switched switches)))	DERWENT;	
			IBM_TDB	
,	1284	("5" and (((relay relays relayed relaying switch switching switched	USPAT;	2003/06/10 14:47
2	120.	switches) with circuit) and ((fanout "fan out" serial-to-parallel	US-PGPUB;	
		multiplex\$3) near (relay relays relayed relaying switch switching	EPO; JPO;	
1		switched switches)))) and (latch and clock)	DERWENT;	
		Switched Switchessyy) ) and (with the same server)	IBM TDB	
	1403	((DUT "device under test" device-under-test CUT "circuit under test"	USPĀT;	2003/06/10 12:59
,	1403	circuit-under-test SUT "system under test" system-under-test) and (test	US-PGPUB;	
	-	near (data signal input pattern source information))).ti. ((DUT "device	ЕРО; ЈРО;	
		under test" device-under-test CUT "circuit under test" circuit-under-test	DERWENT;	
		SUT "system under test" system-under-test) and (test near (data signal	IBM_TDB	*
1		input pattern source information))).ab.		
		input pattern source information))).au.  (((DUT "device under test" device-under-test CUT "circuit under test"	USPAT;	2003/06/10 12:59
-	68	(((DU) "device under lest device-under-lest CO1" cheunt under test) and (test	US-PGPUB;	20031001101
	•	circuit-under-test SUT "system under test" system-under-test) and (test	EPO; JPO;	
		near (data signal input pattern source information))).ti. ((DUT "device	DERWENT;	
		under test" device-under-test CUT "circuit under test" circuit-under-test		
		SUT "system under test" system-under-test) and (test near (data signal	IBM_TDB	
		input pattern source information))) ab.) and (relay relays)	LICDAT.	2003/06/09 11:56
-	310	(((DUT "device under test" device-under-test CUT "circuit under test"	USPAT;	2003/00/09 11:30
İ		circuit-under-test SUT "system under test" system-under-test) and (test	US-PGPUB;	
		near (data signal input pattern source information))).ti. ((DUT "device	EPO; JPO;	
İ		under test" device-under-test CUT "circuit under test" circuit-under-test	DERWENT;	
		SUT "system under test" system-under-test) and (test near (data signal	IBM_TDB	
		input pattern source information))).ab.) and (relay relays switch		
		switches)		
_	60	((((DUT "device under test" device-under-test CUT "circuit under test"	USPAT;	2003/06/09 16:21
		circuit-under-test SUT "system under test" system-under-test) and (test	US-PGPUB;	
		near (data signal input pattern source information))).ti. ((DUT "device	EPO; JPO;	
		under test" device-under-test CUT "circuit under test" circuit-under-test	DERWENT;	
		SUT "system under test" system-under-test) and (test near (data signal	IBM_TDB	
		input pattern source information))).ab.) and (relay relays switch	_	
		switches)) and ((clock clocks) with (latch "shift register" flip-flop		
		flipflop register))		
-	005		USPAT;	2003/06/09 12:00
	885	/14//04.0018.	US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
		CONTROLL	USPAT;	2003/06/09 12:0
-	0	(((((DUT "device under test" device-under-test CUT "circuit under test"	US-PGPUB;	2005100107 12.0
		circuit-under-test SUT "system under test" system-under-test) and (test	EPO; JPO;	
		near (data signal input pattern source information))).ti. ((DUT "device		
		under test" device-under-test CUT "circuit under test" circuit-under-test	DERWENT;	
		SUT "system under test" system-under-test) and (test near (data signal	IBM_TDB	
	1	input pattern source information))).ab.) and (relay relays switch		
		switches)) and ((clock clocks) with (latch "shift register" flip-flop		
	[	flipflop register))) and (fan-out "fan out" fanout)		
-	1408020	1 4 4 QUIT !!	USPAT;	2003/06/09 16:2
	1.0002	circuit-under-test SUT "system under test" system-under-test	US-PGPUB;	İ
		one and and and and and and and and and and	EPO, JPO,	
			DERWENT;	
			IBM_TDB	
	211	(((DUT "device under test" device-under-test CUT "circuit under test"	USPAT;	2003/06/10 13:0
-	311	circuit-under-test SUT "system under test" system-under-test) and (test	US-PGPUB;	
		near (data signal input pattern source information))).ti. ((DUT "device	EPO; JPO;	
		under test" device-under-test CUT "circuit under test" circuit-under-test	DERWENT;	
		surface system under test cold circuit under test circuit-inder-test SUT "system under test" system-under-test) and (test near (data signal	IBM_TDB	
		input pattern source information))).ab.) and (relay relays switch	15155	
		switches)		

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-	16361	(DUT "device under test" device-under-test CUT "circuit under test"	USPAT; US-PGPUB;	2003/06/10 13:13
		circuit-under-test SUT "system under test" system-under-test) and (test	1	
		near (data signal input pattern source information))	ЕРО; ЛРО;	
		•	DERWENT;	
			IBM_TDB	
*	25770	(DUT "device under test" device-under-test CUT "circuit under test"	USPAT;	2003/06/10 13:54
		circuit-under-test SUT "system under test" system-under-test (circuit	US-PGPUB;	
		near test\$3)) and (test near (data signal input pattern source	ЕРО; ЈРО;	
		information))	DERWENT,	
			IBM TDB	